

PRELIMINARY

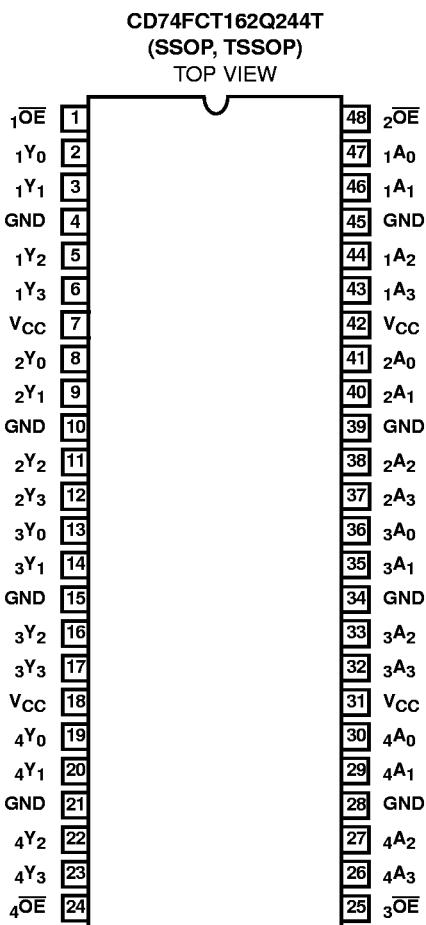
December 1996

Fast, Low Noise CMOS 16-Bit Buffer/Line Driver

Features

- Advanced 0.6 micron CMOS Technology
- $V_{CC} = 5V \pm 10\%$
- Balanced Output Drivers: $\pm 12mA$
- Output Impedance 35Ω (Typical)
- Typical V_{OLP} (Output Ground Bounce) $< 0.5V$ at $V_{CC} = 5V, T_A = 25^\circ C$
- Bus Hold Retains Last Active Bus State During Three-State
- Hysteresis on All Inputs

Pinout



Description

The CD74FCT162Q244T is a non-inverting 16-bit buffer/line driver designed for bus interface applications where low noise operation is essential.

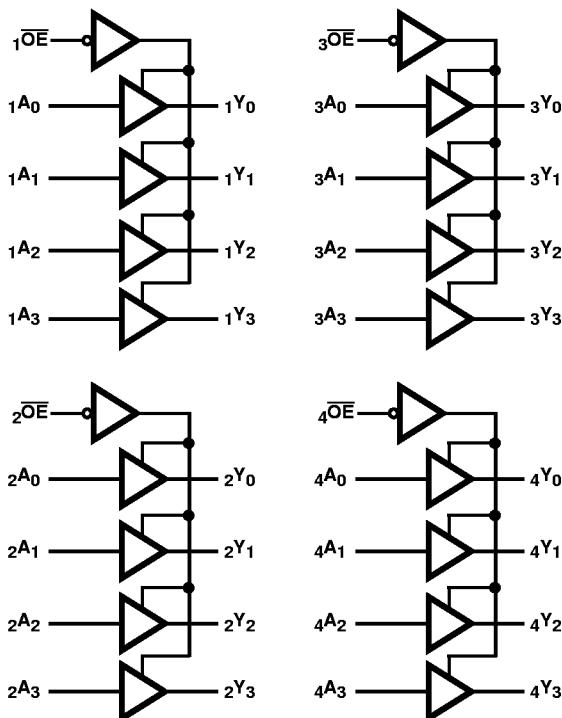
The CD74FCT162Q244T is designed with current limiting resistors at its outputs to control the output edge rate resulting in lower ground bounce and undershoot. This device features a typical output impedance of 35Ω , eliminating the need for external terminating resistors for most bus interface applications. This noise suppression benefit is designated by the letter "Q" (for quiet) in the part number.

The CD74FCT162Q244T also features "Bus Hold" which retains the input's last state whenever the input goes to high-impedance preventing "floating" inputs and eliminating the need for pullup/down resistors.

This high-speed, low power device also features a flow-through organization for ease of board layout. These devices are designed with three-state controls to operate in a Quad-Nibble, Dual-Byte, or a single 16-bit word mode.

Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CD74FCT162Q244TMT	-40 to 85	48 Ld TSSOP	M48.240-P
CD74FCT162Q244ATMT	-40 to 85	48 Ld TSSOP	M48.240-P
CD74FCT162Q244CTMT	-40 to 85	48 Ld TSSOP	M48.240-P
CD74FCT162Q244DTMT	-40 to 85	48 Ld TSSOP	M48.240-P
CD74FCT162Q244ETMT	-40 to 85	48 Ld TSSOP	M48.240-P
CD74FCT162Q244TSM	-40 to 85	48 Ld SSOP	M48.300-P
CD74FCT162Q244ATSM	-40 to 85	48 Ld SSOP	M48.300-P
CD74FCT162Q244CTSM	-40 to 85	48 Ld SSOP	M48.300-P
CD74FCT162Q244DTSM	-40 to 85	48 Ld SSOP	M48.300-P
CD74FCT162Q244ETSM	-40 to 85	48 Ld SSOP	M48.300-P

Functional Block Diagram

TRUTH TABLE (NOTE 1)

INPUTS		OUTPUTS
$x\bar{OE}$	xA_x	xY_x
L	L	L
L	H	H
H	X	Z

NOTE:

1. H = High Voltage Level
- L = Low Voltage Level
- X = Don't Care
- NC = No Change
- Z = High Impedance

Pin Descriptions

PIN NAME	DESCRIPTION
$x\bar{OE}$	Three-State Output Enable Inputs (Active LOW)
xA_x	Inputs (Note 2)
xY_x	Three-State Outputs
GND	Ground
V_{CC}	Power

NOTE:

2. For the CD74FCT162Q244T, these pins have "Bus Hold". All other pins are standard, outputs, or I/Os.

Absolute Maximum Ratings

DC Input Voltage	-0.5V to 7.0V
DC Output Current	120mA

Operating Conditions

Operating Temperature Range	-40°C to 85°C
Supply Voltage to Ground Potential	
Inputs and V _{CC} Only	-0.5V to 7.0V
Supply Voltage to Ground Potential	

Outputs and D/O Only	-0.5V to 7.0V
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CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

3. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications

PARAMETER	SYMBOL	(NOTE 4) TEST CONDITIONS		MIN	(NOTE 5) TYP	MAX	UNITS
DC ELECTRICAL SPECIFICATIONS Over the Operating Range, T _A = -40°C to 85°C, V _{CC} = 5.0V ±10%							
Input HIGH Voltage	V _{IH}	Guaranteed Logic HIGH Level		2.0	-	-	V
Input LOW Voltage	V _{IL}	Guaranteed Logic LOW Level		-	-	0.8	V
Input HIGH Current	I _{IH}	Standard Input V _{CC} = Max	V _{IN} = V _{CC}	-	-	1	μA
Input HIGH Current	I _{IH}	Bus Hold Input (Note 7) V _{CC} = Max	V _{IN} = V _{CC}	-	-	±100	μA
Input LOW Current	I _{IL}	Standard Input V _{CC} = Min	V _{IN} = GND	-	-	-1	μA
Input LOW Current	I _{IL}	Bus Hold Input (Note 7) V _{CC} = Min	V _{IN} = GND	-	-	±100	μA
Bus Hold Sustain Current	I _{BHH} I _{BHL}	Bus Hold Input (Note 7) V _{CC} = Min	V _{IN} = 2.0V V _{IN} = 0.8V	-50 50	-	-	μA
High Impedance Output Current (Three-State) (Note 9)	I _{OZH} I _{OZL}	V _{CC} = Max	V _{OUT} = V _{CC} V _{OUT} = GND	-	-	1 -1	μA
Clamp Diode Voltage	V _{IK}	V _{CC} = Min, I _{IN} = -18mA		-	-0.7	-1.2	V
Output Drive Current	I _O	V _{CC} = Max (Note 6), V _{OUT} = 2.5V		-50	-	-180	mA
Input Hysteresis	V _H			-	100	-	mV
OUTPUT DRIVE SPECIFICATIONS Over the Operating Range							
Output LOW Current	I _{ODL}	V _{CC} = 5V, V _{IN} = V _{IH} or V _{IL} , V _{OUT} = 1.5V (Note 6)		36	-	-	mA
Output HIGH Current	I _{ODH}	V _{CC} = 5V, V _{IN} = V _{IH} or V _{IL} , V _{OUT} = 1.5V (Note 6)		-100	-166	-200	mA
Output HIGH Voltage	V _{OH}	V _{CC} = Min, V _{IN} = V _{IH} or V _{IL}	I _{OH} = -12.0mA	2.4	3.3	-	V
Output LOW Voltage	V _{OL}	V _{CC} = Min, V _{IN} = V _{IH} or V _{IL}	I _{OL} = 12.0mA	-	0.4	0.55	V
CAPACITANCE T _A = 25°C, f = 1MHz							
Input Capacitance (Note 9)	C _{IN}	V _{IN} = 0V		-	4.5	6	pF
Output Capacitance (Note 9)	C _{OUT}	V _{OUT} = 0V		-	5.5	8	pF
POWER SUPPLY SPECIFICATIONS							
Quiescent Power Supply Current	I _{CC}	V _{CC} = Max	V _{IN} = GND or V _{CC}	-	0.1	500	μA
Supply Current per Input at TTL HIGH	ΔI _{CC}	V _{CC} = Max	V _{IN} = 3.4V (Note 10)	-	0.5	1.5	mA

Electrical Specifications (Continued)

PARAMETER	SYMBOL	(NOTE 4) TEST CONDITIONS				MIN	(NOTE 5) TYP	MAX	UNITS
Supply Current per Input per MHz (Note 11)	I _{CCD}	V _{CC} = Max, Outputs Open xOE = GND One Bit Toggling 50% Duty Cycle		V _{IN} = V _{CC} V _{IN} = GND		-	60	100	µA/MHz
Total Power Supply Current (Note 13)	I _C	V _{CC} = Max, Outputs Open f _I = 10MHz, 50% Duty Cycle xOE = GND One Bit Toggling		V _{IN} = V _{CC} V _{IN} = GND	-	0.6	1.5 (Note 12)	mA	
				V _{IN} = 3.4V V _{IN} = GND	-	.9	2.3 (Note 12)	mA	
		V _{CC} = Max, Outputs Open f _I = 2.5MHz 50% Duty Cycle xOE = GND 16 Bits Toggling		V _{IN} = V _{CC} V _{IN} = GND	-	2.4	4.5 (Note 12)	mA	
				V _{IN} = 3.4V V _{IN} = GND	-	6.4	16.5 (Note 12)	mA	

Switching Specifications Over Operating Range

PARAMETER	SYMBOL	(NOTE 14) TEST CONDITIONS	T		AT		CT		DT		ET		UNITS
			(NOTE 15) MIN	MAX									
Propagation Delay xAx to xY _X	t _{PLH} , t _{PHL}	C _L = 50pF R _L = 500Ω	1.5	6.5	1.5	4.8	1.5	4.1	1.5	3.8	1.5	3.2	ns
Output Enable Time xOE to xAx or xY _X	t _{PZH} , t _{PZL}		1.5	8.0	1.5	6.2	1.5	5.8	1.5	4.8	1.5	4.4	ns
Output Disable Time (Note 16) xOE to xAx or xY _X	t _{PHZ} , t _{PLZ}		1.5	7.0	1.5	5.6	1.5	5.2	1.5	4.0	1.5	4.0	ns
Output Skew (Note 17)	t _{SK(O)}		-	0.5	-	0.5	-	0.5	-	0.5	-	0.5	ns

NOTES:

4. For conditions shown as Max or Min, use appropriate value specified under Electrical Specifications for the applicable device type.
5. Typical values are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
6. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.
7. Pins with Bus Hold are identified in the pin description.
8. This specification does not apply to bi-directional functionalities with Bus Hold.
9. This parameter is determined by device characterization but is not production tested.
10. Per TTL driven input (V_{IN} = 3.4V); all other inputs at V_{CC} or GND.
11. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
12. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
13. I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}

$$I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + f_I N_I)$$

$$I_{CC} = \text{Quiescent Current}$$

$$\Delta I_{CC} = \text{Power Supply Current for a TTL High Input (V}_IN = 3.4V)$$

$$D_H = \text{Duty Cycle for TTL Inputs High}$$

$$N_T = \text{Number of TTL Inputs at D}_H$$

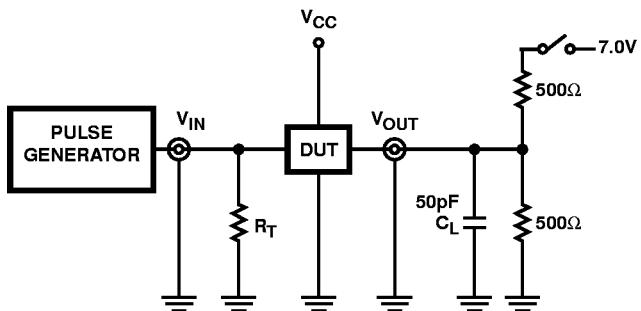
$$I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$$

$$f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$$

$$f_I = \text{Input Frequency}$$

$$N_I = \text{Number of Inputs at f}_I$$

All currents are in millamps and all frequencies are in megahertz.
14. See test circuit and wave forms.
15. Minimum limits are guaranteed but not tested on Propagation Delays.
16. This parameter is guaranteed but not production tested.
17. Skew between any two outputs, of the same package, switching in the same direction. This parameter is guaranteed by design.

Test Circuits and Waveforms**SWITCH POSITION**

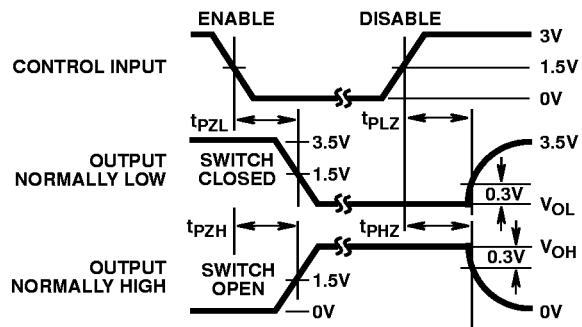
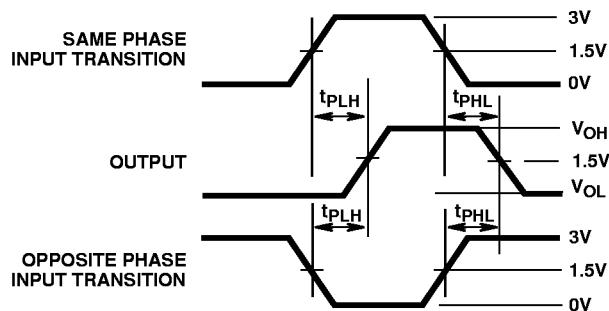
TEST	SWITCH
t_{PLZ}, t_{PZL}	Closed
$t_{PHZ}, t_{PZH}, t_{PLH}, t_{PHL}$	Open

DEFINITIONS:

C_L = Load capacitance, includes jig and probe capacitance.
 R_T = Termination resistance, should be equal to Z_{OUT} of the Pulse Generator.

NOTE:

18. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $Z_{OUT} \leq 50\Omega$;
 $t_f, t_r \leq 2.5\text{ns}$.

FIGURE 1. TEST CIRCUIT**FIGURE 2. ENABLE AND DISABLE TIMING****FIGURE 3. PROPAGATION DELAY**